

台达电子（东莞）有限公司 分析实验室

Delta Electronics (Dong Guan)
Analysis Lab

2021/03/09



研发中心二楼

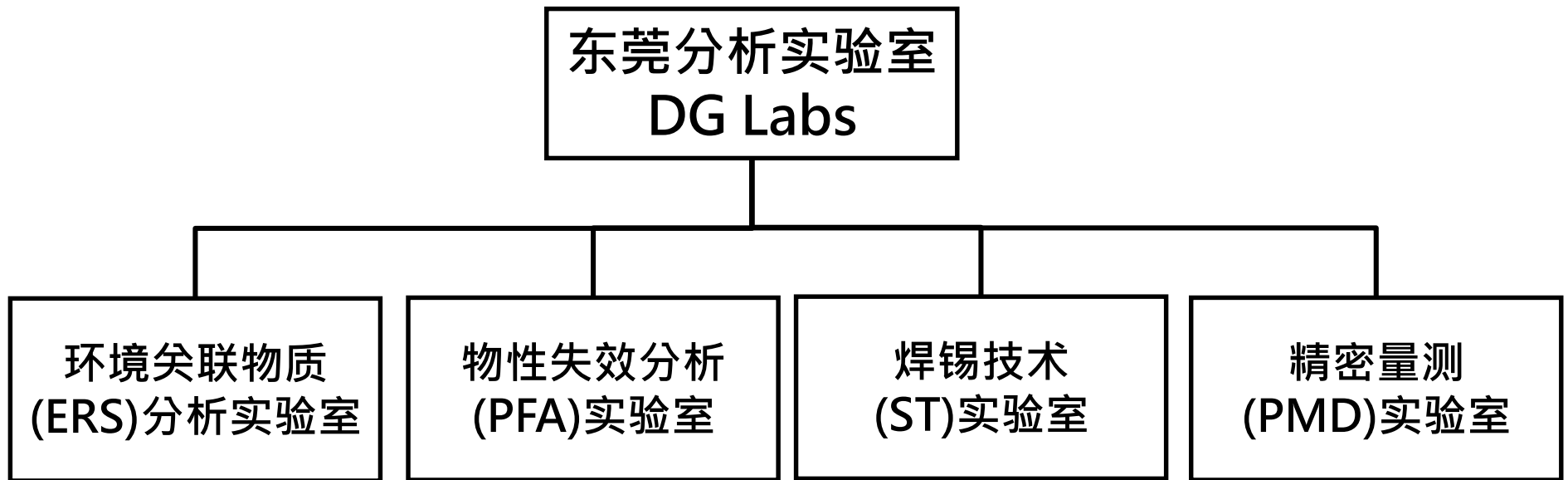
R & D Building Exterior



實驗室座落在二樓
Labs on the second floor



科学严谨 客观公正 准确可靠 客户满意





CNAS L5971

東莞分析實驗室 Dongguan Guangdong Analysis Lab

實驗室功能 Lab Function



物性失效分析實驗室
Physical Failure
Analysis Lab
(PFA Lab)

3D X-Ray檢測
(3D X-ray)

非破壞性分析
Non-destructive
Analysis

破壞性分析
Destructive
Analysis

應變測試
Strain gage Test

半導體分析
Semiconductor FA

環境關聯物質分析實驗室
Environment Related
Substance Analysis
Lab
(ERS Lab)

阻燃性測試
Flame retardants test

邻苯二甲酸檢測
Phthalates test

重金屬檢測
Heavy Metal test

離子污染度檢測
Ionic Analysis of
Circuit Boards

鹵素檢測
Halogen test

焊錫技術實驗室
Solder Technology Lab
(ST Lab)

合金成分檢測
Alloy Composition
Test

錫膏特性檢測
Solder paste
Characteristics

可焊性檢測
Solder ability Test

推拉力檢測
Pull & Push Test

離子污染度檢測
Ionic Contamination
Test

精密量測實驗室
Precision Measurement
Department Lab
(PMD Lab)

三次元測量系統
Coordinate
Measurement system

3D掃描測量系統
3D scanner
measurement system

高度計測量系統
Height gauge
measurement system

卡尺校驗系統
Caliper calibration
system

千分尺校驗系統
Micrometer
calibration system



中国合格评定国家认可委员会 实验室认可证书

(注册号: CNAS L5971)

兹证明:

台达电子电源(东莞)有限公司分析实验室

(法人: 台达电子电源(东莞)有限公司)

广东省东莞市石碣镇台达工业区台达三厂, 523308

符合 ISO/IEC 17025: 2005《检测和校准实验室能力的通用要求》
(CNAS-CL01《检测和校准实验室能力认可准则》)的要求, 具备承担本
证书附件所列服务能力, 予以认可。

获认可的能力范围见标有相同认可注册号的证书附件, 证书附件是
本证书组成部分。

生效日期: 2018-11-20

截止日期: 2024-12-17



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China National Accreditation Service for Conformity Assessment LABORATORY ACCREDITATION CERTIFICATE (Registration No. CNAS L5971)

Delta Electronics Power (Dongguan) Co., Ltd.

Analysis Laboratory

(Legal Entity: Delta Electronics Power (Dongguan) Co., Ltd.)

Delta Plant 3, Delta Industrial Estate, Shijie, Dongguan, Guangdong, China

is accredited in accordance with ISO/IEC 17025: 2005 General Requirements for the Competence of Testing and Calibration Laboratories (CNAS-CL01 Accreditation Criteria for the Competence of Testing and Calibration Laboratories) for the competence to undertake the service described in the schedule attached to this certificate.

The scope of accreditation is detailed in the attached schedule bearing the same registration number as above. The schedule forms an integral part of this certificate.

Effective Date: 2018-11-20

Expiry Date: 2024-12-17

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1. 金属元素检测

(Metallic element test)

铅(Pb)、镉(Cd)、汞(Hg)、砷(As)、铬(Cr)、锑(Sb)、铍(Be)、磷(P)....

材料 (Material) :

塑料 (Plastic)

橡胶 (rubber)

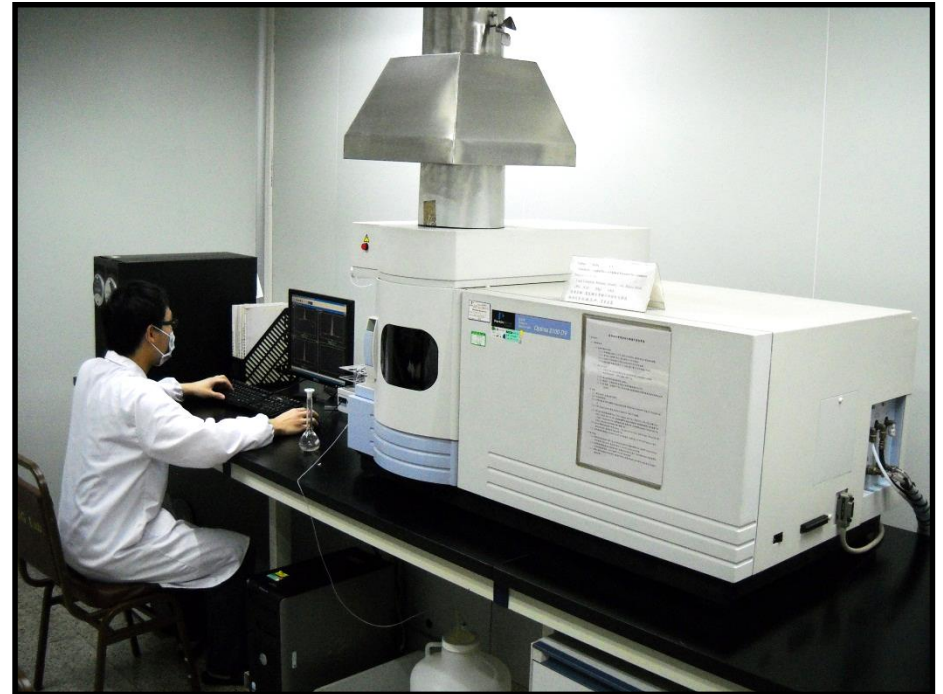
金属 (Metal) ...

测试方法 (Test method) :

IEC 62321

EPA3050B

EPA3052 ◦



ICP-OES (感应耦合等离子体发射光谱仪)

2. 六价铬检测

(Cr^{6+} test) 。

材料 (Material) :

塑料 (Plastic)

金属表面镀层

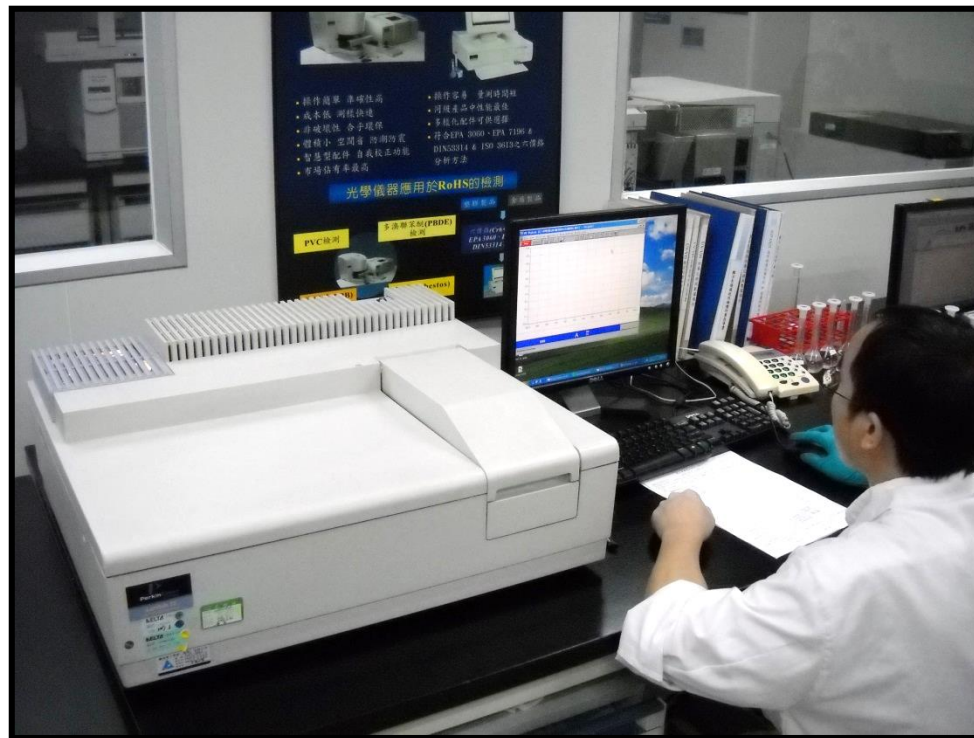
(Metal surface coating) ,

金属 (Metal) ...

测试方法 (Test method) :

IEC 62321-7-1

IEC 62321-7-2



UV-VIS (紫外光-可见光光谱仪)

3. 多溴联苯&多溴联苯醚检

(PBB&PBDE test) °

材料 (Material) :

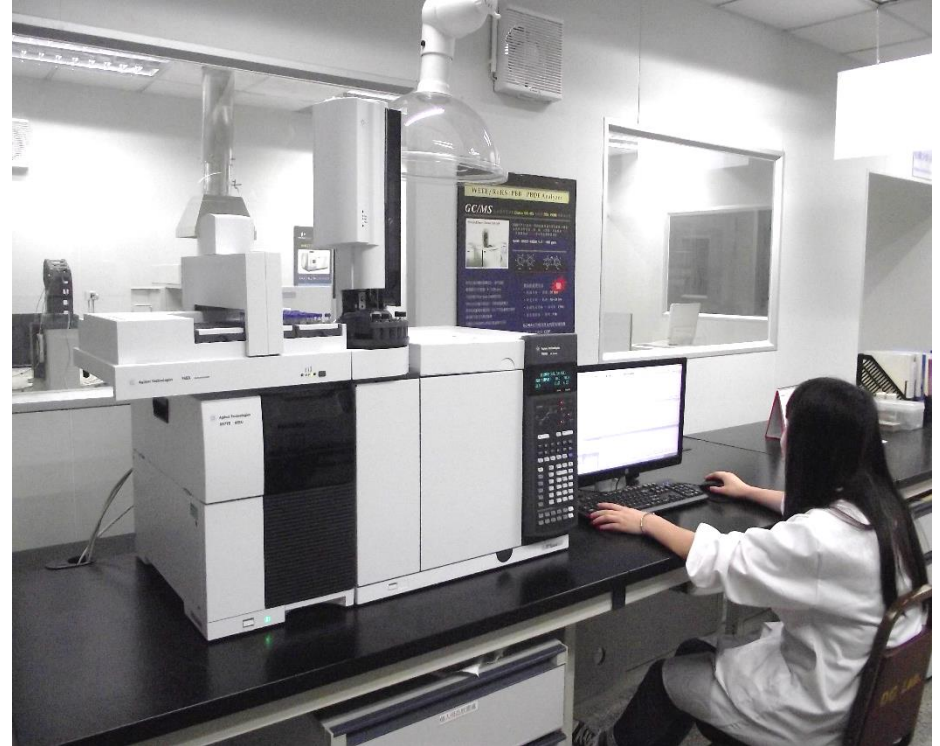
塑料 (Plastic)

橡胶 (rubber) ...

测试方法 (Test method) :

IEC 62321

EPA 3550C



GC-MS (气相色谱-质谱联用仪)

4. 邻苯二甲酸酯&六溴环十二烷检测。 (Phthalate & HBCDD test)

材料 (Material) :
塑料 (Plastic)
橡胶 (rubber) ...

测试方法 (Test method) :
EN14372
EPA3550C



GC-MS (气相色谱-质谱联用仪)

5. 卤素 & 其它阴离子检测 (Halogen & other anion test)

材料 (Material) :
塑料 (Plastic)
橡胶 (rubber) ...

测试方法 (Test method) :
EN 14582

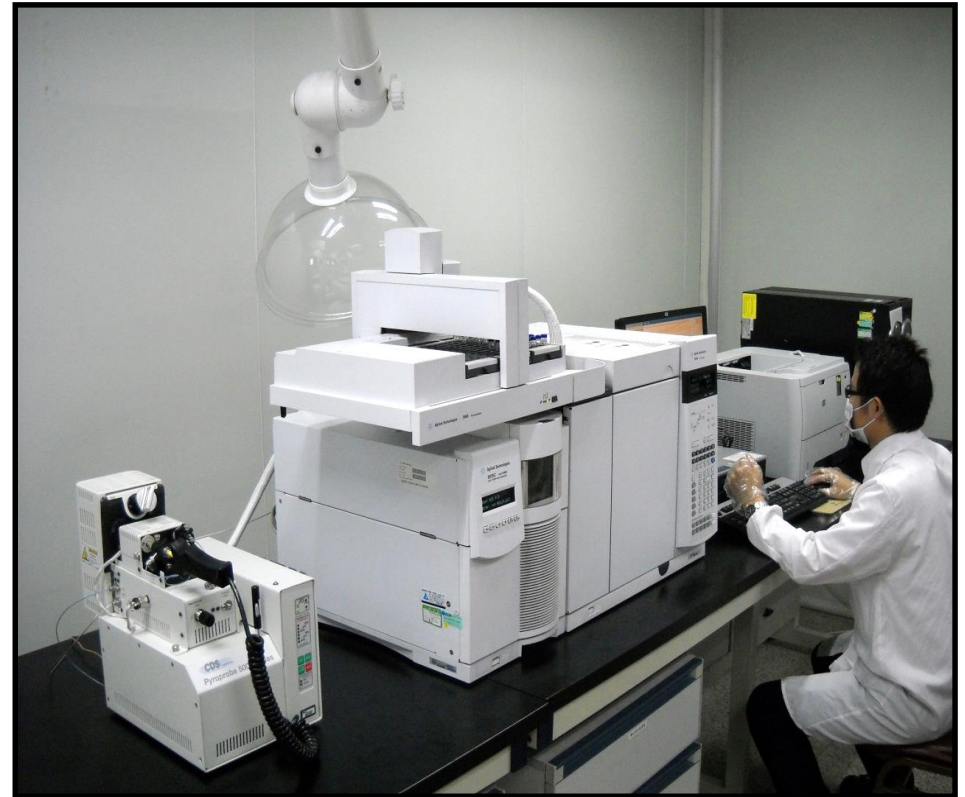


IC 离子色谱仪

6. 红磷检测。 (Red phosphorus test)

材料 (Material) :
塑料 (Plastic)
橡胶 (rubber) ...

测试方法 (Test method) :
PY-GC/MS

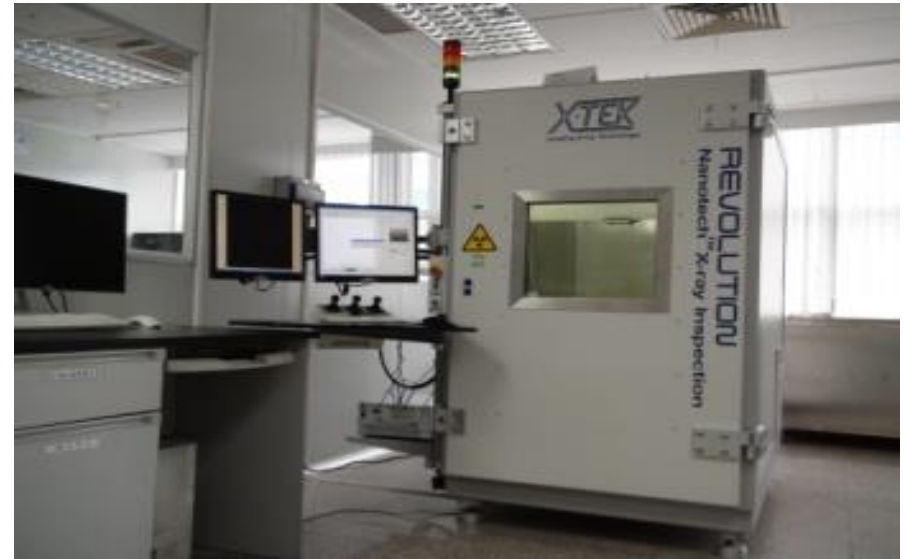


PY-GC/MS (热裂解-气象色谱/质谱联用仪)

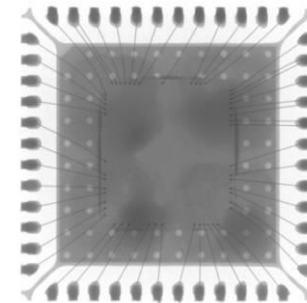
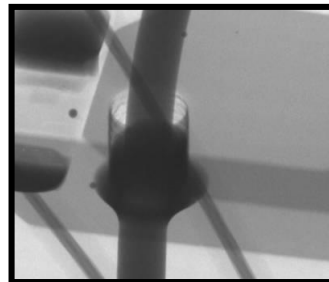
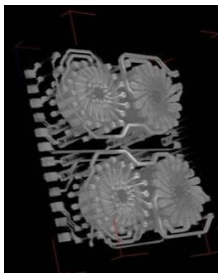
1.X-ray穿透检查(X-ray Inspection)

3D X-Ray检测仪 (3D X-Ray system)

- 元器件内部结构检
(Components internal inspection)
- 连接线材
(Wire bonding inspection)
- 各类焊点质量检
(Solder joint quality inspection)
- PCB内部检
(PCB Internal inspection)



3D X-ray检测仪

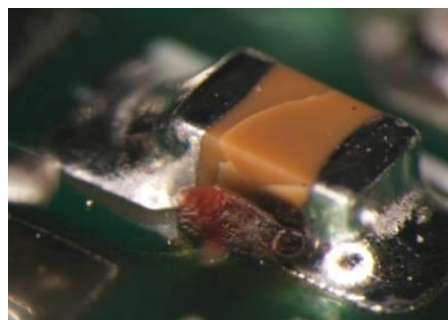
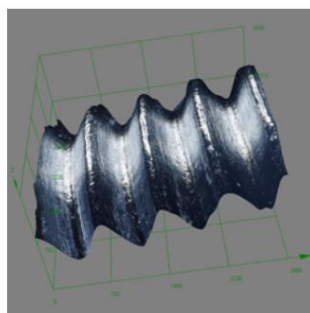
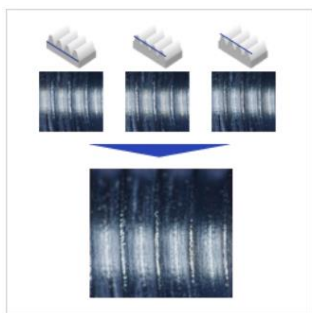


2. 外观检查 (Visual Inspection)

- 元器件外观检测
(Components appearance inspection)
- 焊点检测
(Solder joint appearance inspection)
- PCBA外观检测
(PCBA appearance inspection)



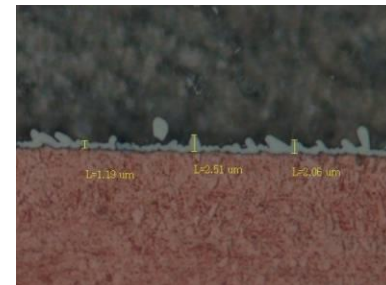
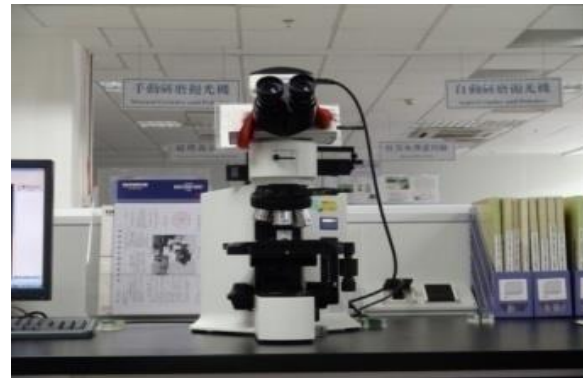
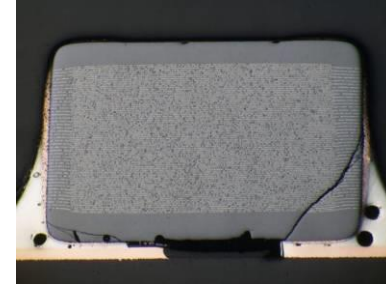
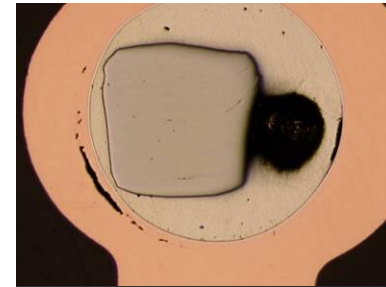
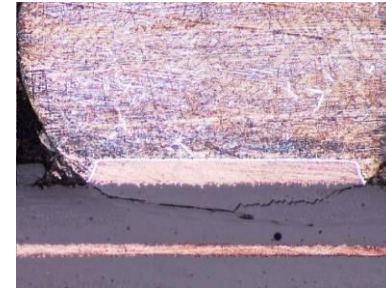
景深扩展 & 3D 观测分析



外觀缺陷檢查

3. 切片实验 (Cross Section Analysis):

- 抛光研磨机 (Polishing grinding M/C)
 - 各类金相样品
(All kinds of metallographic specimen)
 - 抛光
(Auto Polisher)
- 金相显微镜 (Metalloscope)
 - 焊点金相分析
(solder joint status)
 - PCB分析量测
(PCB copper thickness measurement)
 - 镀层分析量测
(solder joint status)
 - MLCC金相分析
(MLCC Analysis)
 - 其他金相分析
(Other Cross Section Analysis)

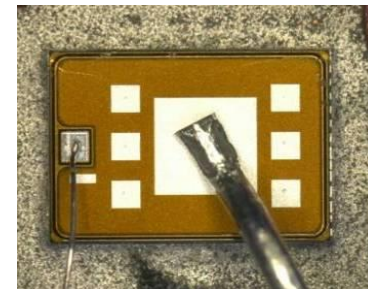
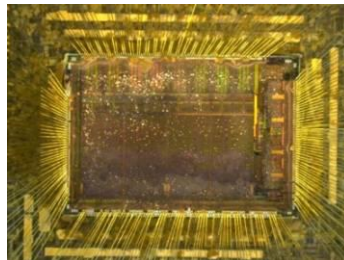
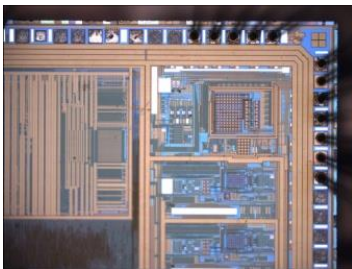
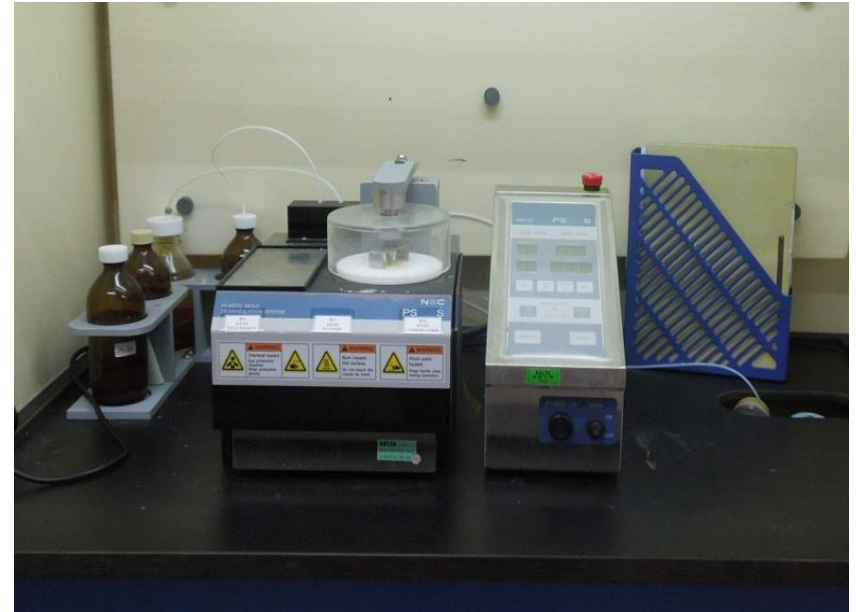


4. 解封胶实验 (Decap Analysis):

自动开封机

(Auto decapsulation M/C)

- BGA/MOSFET 器件
(BGA/MOSFET component)
- Decap 分析
(Decap Analysis)
- 其他器件Decap分析 (Other decap analysis of semiconductor)



5. 红墨水试验(Dye & Pry Test):

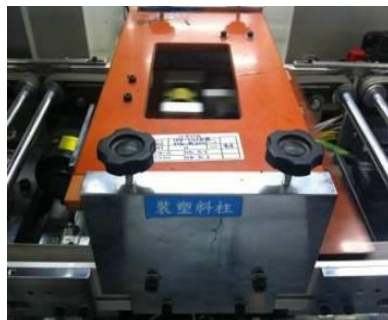
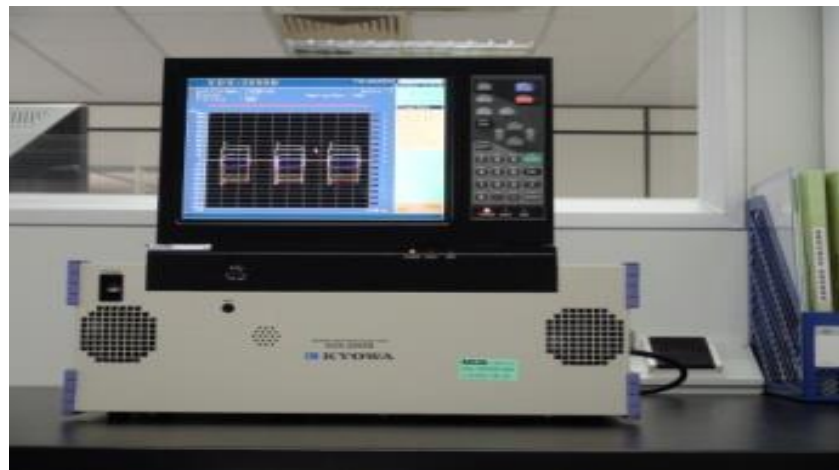
抽真空系统 (Vacuum system)

- BGA/QFN器件染色实验分析 (BGA/QFN Dye & Pry Test)
- 其他器件染色实验分析 (Other components Dye & Pry Test)



6. 应变测试实验 (Strain gage measurement):

- PCBA生产制程热应变验证
(Thermal strain measurement)
- PCBA生产治具应变验证
(Fixture strain measurement)
- 产品可靠度测试应变测试
(Reliability strain test)



7. 半导体失效分析 (Semiconductor Fail Analysis)

7.1 电性测量 (Electrical Measurement)

- Diode、BJT、FET等分立器件静态参数测量
(Diode、BJT、FET and other static parameters measurement)

Diode : V_F 、 I_F 、 V_R 、 I_R 、 V_Z 、 I_{ZT} 、 Z_{ZT} 、 I_{ZK} 、 Z_{ZK} 、
 I_F-V_F 、 I_R-V_R 、 $I_{ZT}-V_{ZT}$

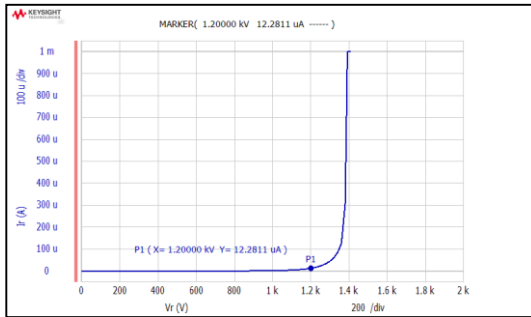
BJT : BV_{CBO} 、 BV_{CEX} 、 BV_{CEO} 、 BV_{EBO} 、 BV_{ECX} 、
 BV_{ECO} 、 I_{CBO} 、 I_{CEX} 、 I_{EBO} 、 $V_{CE(sat)}$ 、 $V_{BE(sat)}$ 、
 $V_{BE(on)}$ 、 H_{FE} 、 I_C-V_{CE}

MOSFET : $V_{(BR)DSS}$ 、 I_{DSS} 、 I_{GSS} 、 $V_{GS(th)}$ 、 $R_{DS(on)}$ 、
 I_{SD} 、 V_{SD} 、 $V_{(BR)GSO}$ 、 I_D-V_{DS} 、 I_D-V_{GS} 、 $R_{DS(on)-I_D}$ 、
 $V_{DS}-I_{SD}$

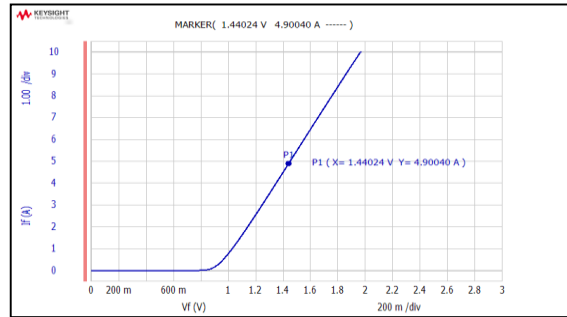


功率器件分析仪/曲线追踪仪
Power Device Analyzer/Curve Tracer

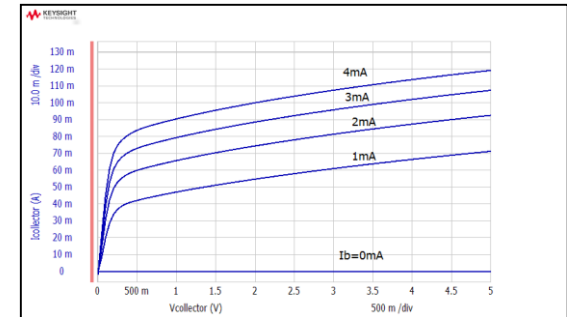
7.1 电性测量 (Electrical Measurement)



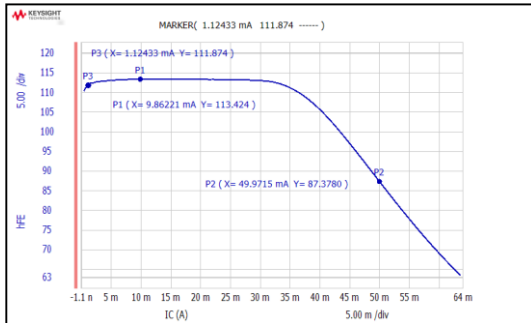
$I_R - V_R$



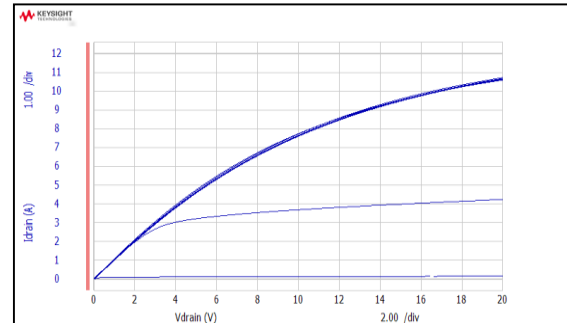
$I_F - V_F$



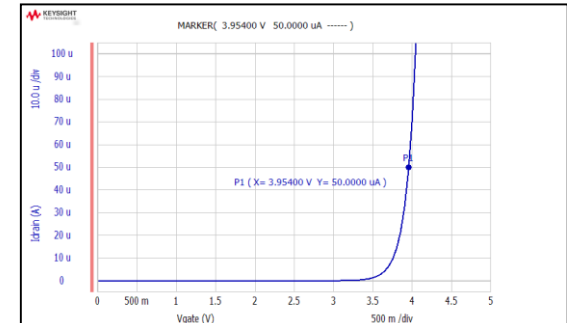
$I_C - V_{CE}$



h_{FE}



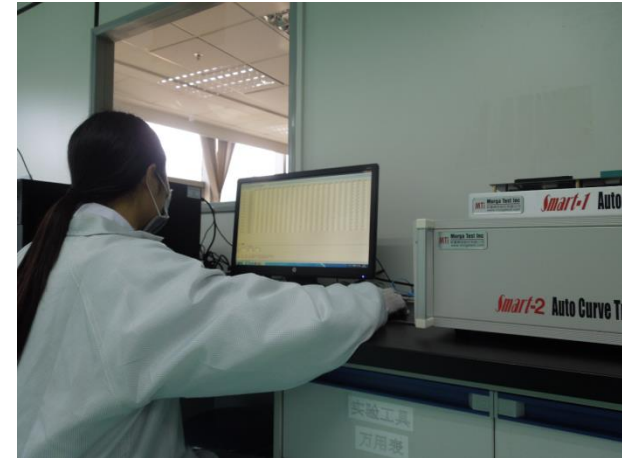
$I_D - V_{DS}$



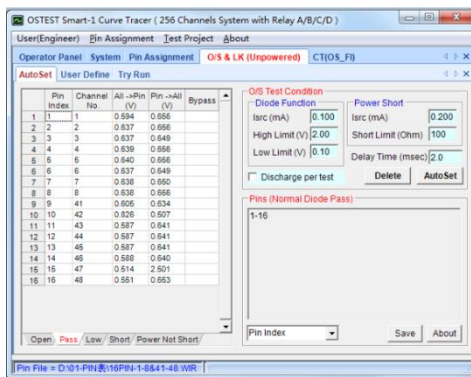
$V_{GS(th)}$

7.1 电性测量 (Electrical Measurement)

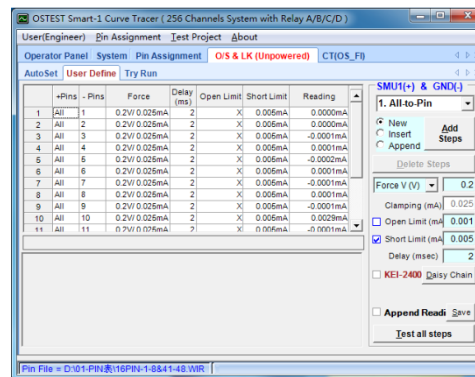
- 针对IC进行 O/S 测试以及Unpowered Leakage 测试可进行绘制IV曲线
(Open/short、 Unpowered Leakage and I/V measurement of integrated circuit)



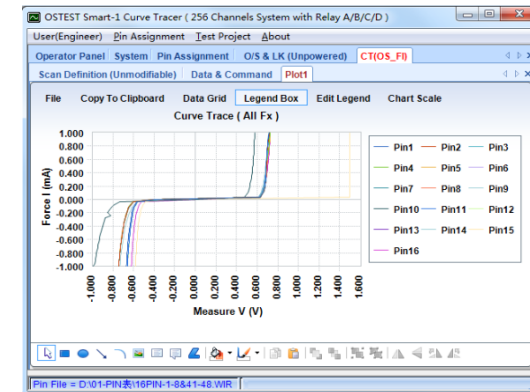
IV曲线量测仪 (IV Curve Tracer)



O/S Test



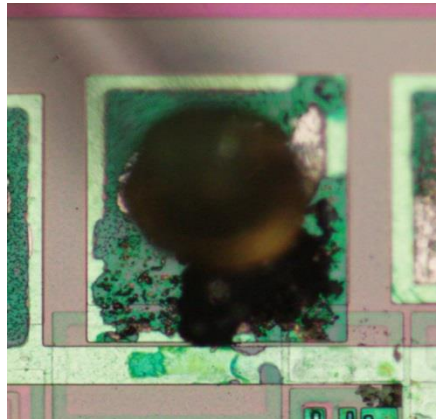
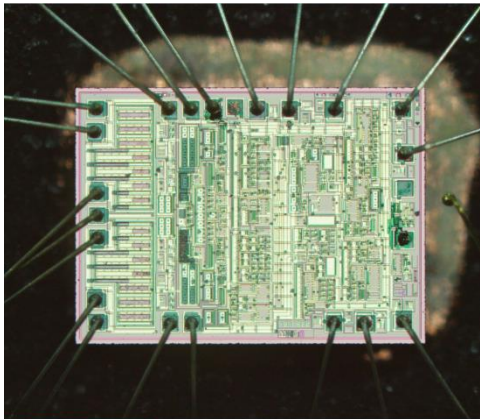
Unpowered Leakage Test



Curve Tracer Test

7.2 Decap后常规显微镜观察 (The inspection after Decap)

- 芯片表面直接观察
(Direct observation of the surface of the chip)
- 烧痕点 (Burn mark)
- 裂痕 (Crack)



金相顯微鏡
(Metallographic Microscope)

物性失效分析实验室 (PFA Lab)

7.3 Decap后液晶显示观察 (Decap liquid crystal display observation)

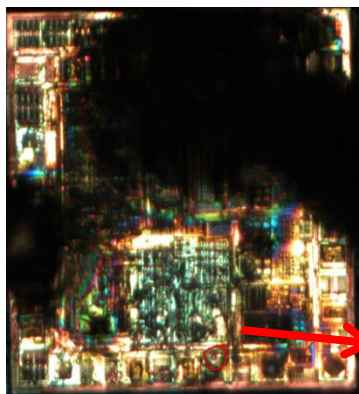
- 芯片表面间接观察
(The chip surface indirect observation)
- 针对金像显微镜观察不到的点进行LC显示观察如ESD造成的失效点 (To observe the metallographic microscope can not see the point Such as the failure point caused by ESD)



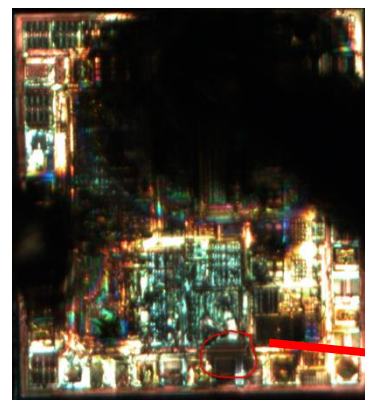
LC液晶探针台 (Liquid Crystal Probe Station)



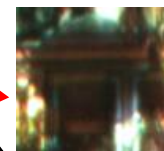
IC加电前
(IC before Power)



IC加电后
(IC after Power)₂

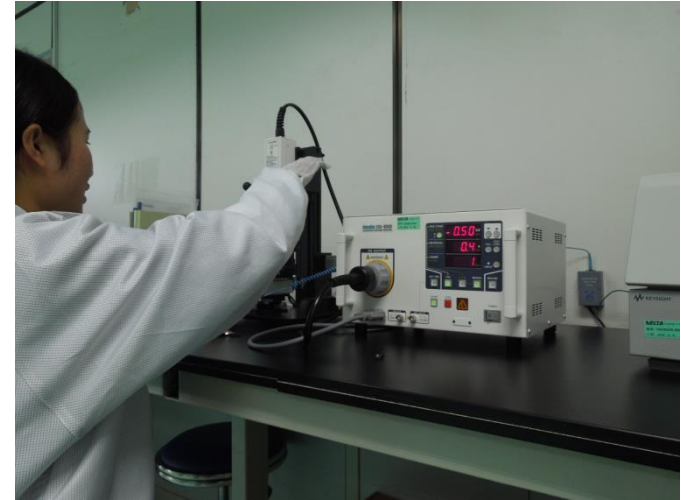


IC加大加电后
(IC increase Power)

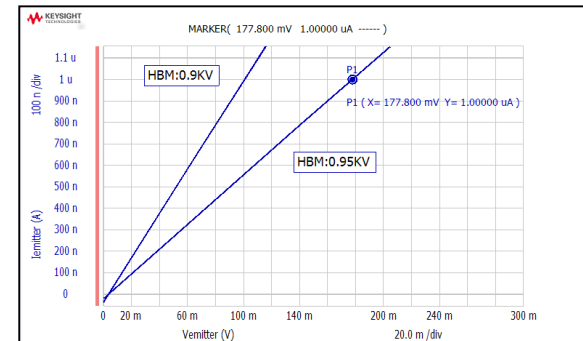
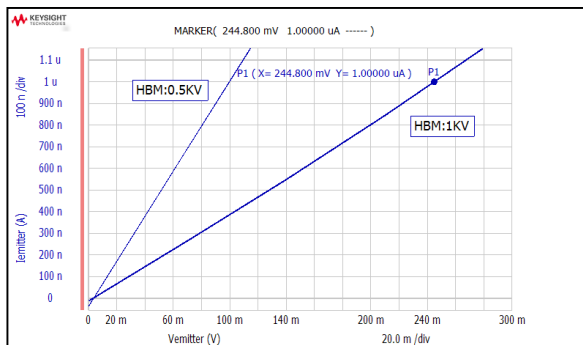


7.4 ESD测试实验 (Electrostatic Discharge Test)

- HBM、MM两种静电放电模式静电失效现象再现
 器件耐静电等级判断
 (HBM, MM two kinds of electrostatic discharge model、Reproduce the failure Phenomenon caused by ESD and Electrostatic rating of devices)



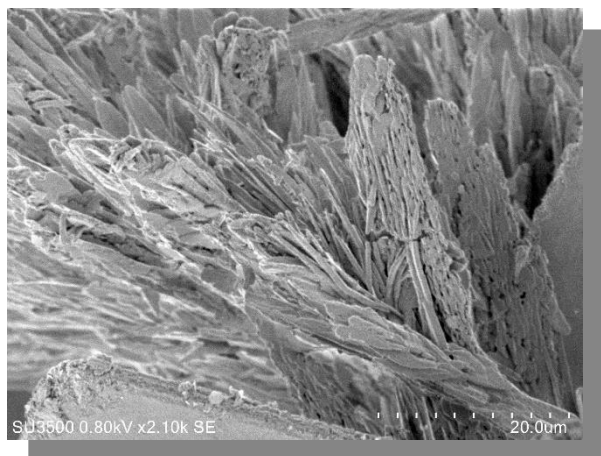
半导体静电放电仿真器
 (ESD Simulator For Semiconductors)



对BJT进行ESD测试前后ICE0变化对比
 (The ESD Test for the BJT)

7.5 SEM/EDS

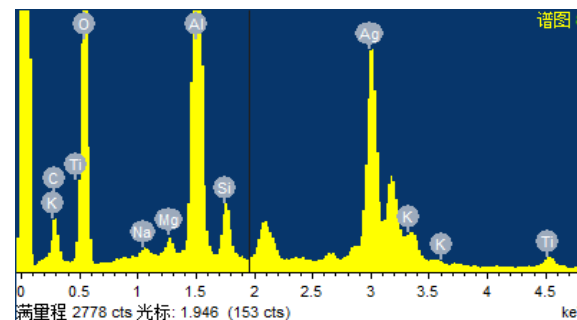
- 电子扫描显微镜/元素分析
(scanning electron microscope/elemental analysis)



超薄面的显微结构
(Microstructure of ultra-thin surface)



Hitachi SU3500
Scanning Electron Microscope



Elements Analysis

1. 焊锡条及炉锡块

(Solder Bar and Used Solder)

- 合金成分及杂质检测
(Alloy Composition Test)
- 润湿性测试
(Wetting Performance Test)
- 扩展率测试
(Spread Test)
- 测试标准

(Testing Standards ANSI IPC/J-STD-001; ANSI IPC/ J-STD-006; JIS Z3282...)

2. 焊锡丝 (Solder Wire)

- 助焊剂含量 (Flux Content)
- 残留物干燥度 (Residues Dryness)
- 喷溅试验 (Splash Test)
- 合金部分成分检测 (Alloy Composition Test)
- 助焊剂部分常规检测 (Flux Test)
- 测试标准 (Testing Standards ANSI IPC/J-STD-006; ANSI IPC/J-STD-004; IPC-TM-650; JIS Z3197; JIS Z3283...)



3. 焊锡膏 (Solder Paste)

- 金属含量 (Metal Content)
- 粘度 (Viscosity)
- 触变系数 (Thixotropic index)
- 锡珠试验 (Solder Ball Test)
- 坍塌试验 (Slump Test)
- 润湿性试验 (Wetting Test)
- 粘附力试验及开封时间 (Tack Test & Open Time)
- 扩展率测试 (Spread Test)
- 合金部分成分及杂质检测 (Alloy Composition Test)
- 助焊剂部分常规检测 (Flux Test)
- 测试标准 Testing Standards ANSI IPC/J-STD-005; ANSI IPC/J-STD-004; IPC-TM-650; JIS Z3197; JIS Z3284..

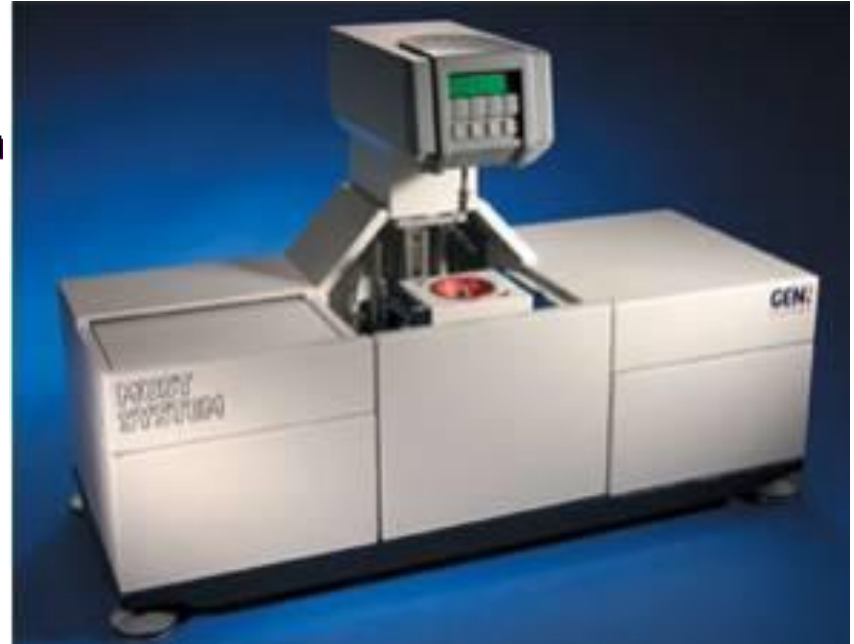
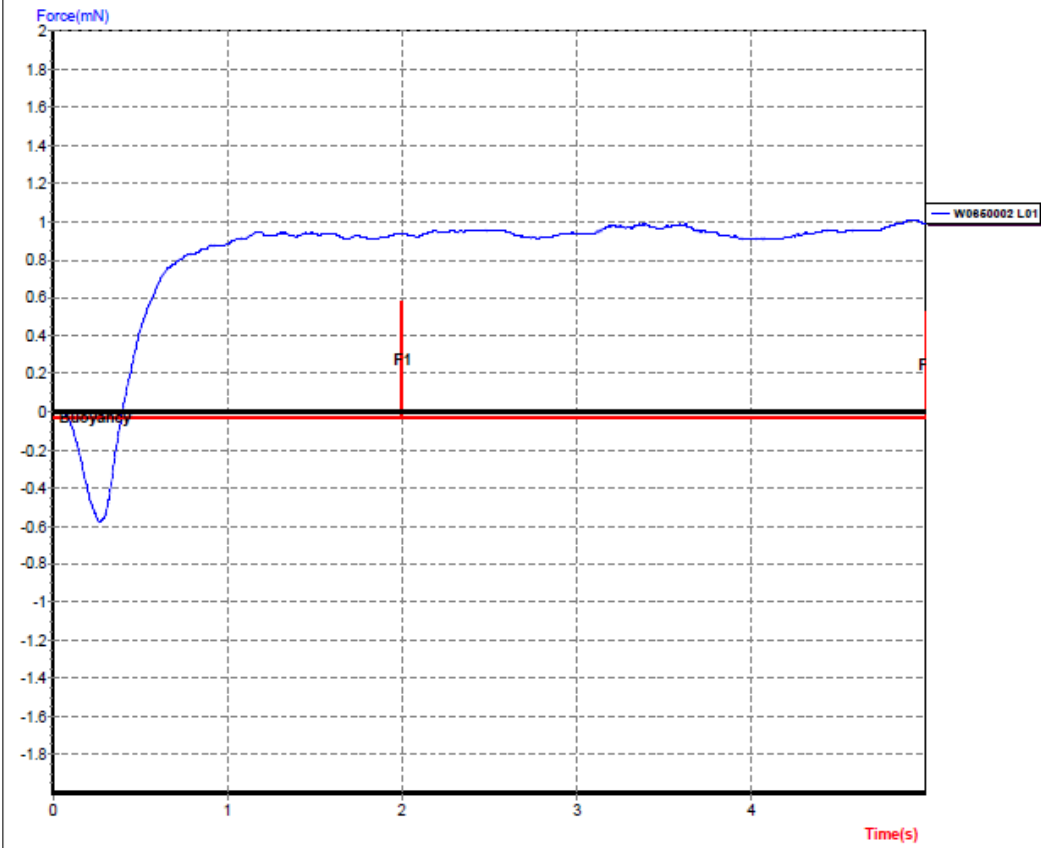


4.助焊剂(Flux)

- 密度/粘度(Density/Viscosity)
- 固体含量 (Nonvolatile Content)
- 扩展率 (Spread Test)
- 残留物干燥度 (Residues Dryness)
- 酸值 (Acid Value)
- 水萃取液电阻率 (Water Solution Resistance Test)
- 测试标准(Testing Standards ANSI IPC/J-STD-004; IPC-TM-650; JIS Z3197; JIS Z3283 GB/T9491..)

5. 元器件可焊性测试 (Component Solderability Test)

Description	Results Filename	Ta (s)	T2/3 (s)	F1 (mN)	F2 (mN)	A.U.C. (mN/s)	DeWet (%)	Pass/Fail
Wire 0.65mm	W0650002 L01	0.396	0.600	0.967	1.019	4.221	2.1	Pass



Wetting Balance

6. 离子污染残留测试 (Ionic Contamination Test)



7. 推拉测试 (Shear Test & Pull Test)

功能：可以針對焊點的強度進行評估

(Function : The strength of the solder joint can be evaluated)



精密量测实验室 (PMD Lab)



单独环境控制(Single independent control)



环境温度 (temperature)	相对湿度 (humidity)
$(20 \pm 1.0) ^\circ\text{C}$	$(50 \pm 15) \%$
照度(Illumination)	震动等级 (Vibration level)
$> 800 \text{ lx}$	Vc-D级



三坐标量测系统 Coordinate Measurement system

厂牌 (Label):	Germany WENZEL
型号 (Model) :	LH 65
量测范围 Measuring range:	(650×750×500) mm
精度(Precision) :	$(1.9 + L / 350) \mu\text{m}$, L unit: mm
量测类型 Measurement type:	各种模具、夹治具、零组件等产品之几何尺寸以及形位尺寸 All kinds of mold ,clip fixture, components of products such as geometry size and form size



精密量测实验室 (PMD Lab)

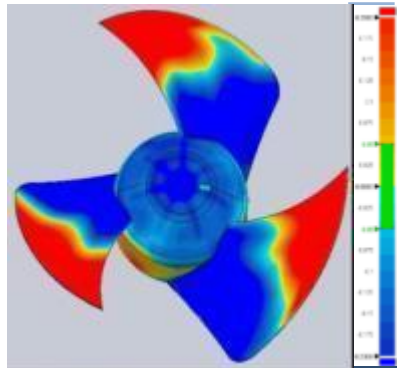
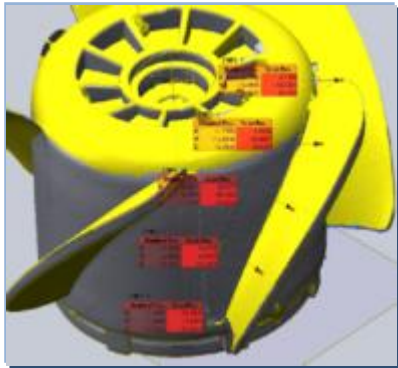


影像量测系统

Vision measurement system

厂牌 (Label):	Mitutoyo
型号 (Model) :	QV-X606P1L-C
量测范围 Measuring range:	(600 × 650 × 250) mm
精度(Precision) :	XY= (1.5+3L/1000) μ m Z = (1.5+4L/1000) μ m
量测类型 Measurement type:	各种模具、夹治具、零组件等产品之几何尺寸 All kinds of mold, clip fixture ,components of products such as geometry size

精密量测实验室 (PMD Lab)



3D扫描量测系统

3D scanner measurement system

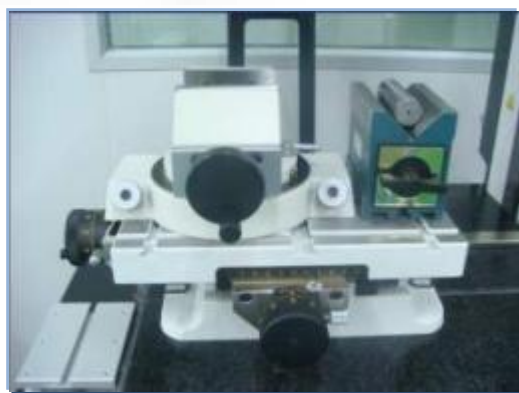
厂牌 (Label): The German Steinbichler

型号 (Model) : COMET 5

量测范围
Measuring range: (200 × 200) mm

精度
(Precision) : 0.02mm

量测类型
Measurement type: 实体扫描, 逆向工程
Body scan,
Reverse engineering



表粗轮廓量测系统

Surface roughness / texture measurement system

厂牌 (Label):	Mitutoyo of Japan
型号 (Model) :	SV-C4100S4
量测范围 Measuring range:	100 mm (X axis)
精度(Precision) :	轮廓直线位移Outline linear displacement: $\pm(0.8+0.01L) \mu\text{m}$, 表粗直线位移Table rough linear displacement: $(0.05+1.5L/1000) \mu\text{m}$
量测类型 Measurement type:	表面粗糙度轮廓量测 Surface roughness Profile measurement



圆度仪量测系统 Roundness measurement test system

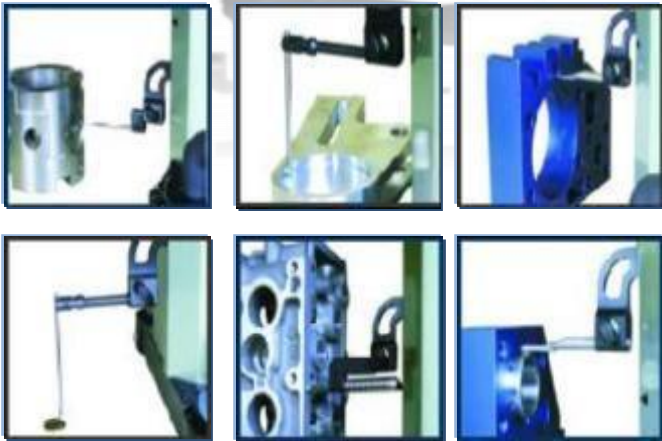
厂牌 (Label):	The German Mahr
型号 (Model):	MarForm MMQ 400-2
量测范围 Measuring range:	(1 to 250) mm
精度(Precision):	$(0.01+0.00025 * H) \mu\text{m}$ H is the measurement height (mm)
量测类型 Measurement type:	真圆度、圆柱度、同心度、同轴度 Roundness, cylindricity ,concentricity ,coaxiality





Altimeter measurement system

厂牌 (Label):	Trimos
型号 (Model) :	VT 600
量测范围 Measuring range:	(0 to 600) mm
精度(Precision) :	$(1.2+L/1000) \mu\text{m}$ L is the measurement height (mm)
量测类型 Measurement type:	高度、深度尺寸; 直径等 Height, diameter, depth;



精密量测实验室 (PMD Lab)



万能试验机测试系统 Universal test machine testing system

厂牌 (Label):

Mester

型号 (Model) :

CMT4000

量测范围

Measuring range:

20 KN

精度(Precision) :

±0.5%

量测类型

Measurement type:

金属及塑料之抗拉、抗压强度；屈服强度；伸长率等

Metal and plastic tensile, compressive strength; yield strength; elongation

检测服务

- ◆ 实验室是利润中心,以提供快捷、准确检测服务为宗旨.
- ◆ 对送测单位及测试结果保密.
- ◆ 一律开立增值税专用发票二联式(可抵税用).

检测时间

一般件 : 3 Days
紧急件 : 1 Day



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